

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination
		10/052,921	LI ET AL.
		Examiner	Art Unit
		Kaj K Olsen	1753

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
B	US-			
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FOREIGN PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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